Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/763,160	HAYASHI ET AL.
Examiner	Art Unit

Jin-Cheng Wang

2672

	SEARCHED				
01	T				
Class	Subclass	Date	Examiner		
345	629	5/22/2005	1CM		
345	156	5/22/2005	JCM		
715	790-791	5/22/2005	JCM		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST	5/22/2005	JCW	
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